### AMENDMENTS TO THE CLAIMS

The following listing of claims will replace all prior versions and listings of claims in the application.

### **LISTING OF CLAIMS**

1. (Currently Amended) A semiconductor device comprising:

### a support base;

an insulating layer formed on the support base;

a semiconductor layer formed on the insulating layer;

a source region formed in the semiconductor layer;

a drain region formed in the semiconductor layer;

a channel region formed between the source region and the drain region in the semiconductor layer;

a gate insulating layer formed above the channel region; and

a gate electrode formed above the gate insulating layer, the gate electrode having a major axis and a minor axis and first and second ends that are spaced apart along the major axis, overlap the semiconductor layer, and are in contact with the insulating layer;

wherein a boundary between the gate insulating layer and the channel region is a wave-like pattern of a gradual slope having crests and troughs alternately spaced apart along the major axis of the gate electrode.

2. (Currently Amended) A semiconductor device comprising:

## a support base;

an insulating layer formed on the support base;

a semiconductor layer formed on the insulating layer;

a source region formed in the semiconductor layer;

a drain region formed in the semiconductor layer;

a channel region formed between the source region and the drain region in the semiconductor layer;

a gate insulating layer formed above the channel region; and

a gate electrode formed above the gate insulating layer, the gate electrode having a major axis and a minor axis and first and second ends that are spaced apart along the major axis, overlap the semiconductor layer, and are in contact with the insulating layer;

wherein a boundary between the gate insulating layer and the channel region is a wave-like pattern without any corners, the wave-like pattern having crests and troughs alternately spaced apart along the major axis of the gate electrode.

3. (Original) The semiconductor device according to Claim 1, wherein a pitch between a top of the wave-like pattern and an adjacent bottom of the wave-like pattern in the boundary is less than or equal to 50 nm.

- 4. (Original) The semiconductor device according to Claim 2, wherein a pitch between a top of the wave-like pattern and an adjacent bottom of the wave-like pattern in the boundary is less than or equal to 50 nm.
- 5. (Original) The semiconductor device according to Claim 1, wherein a part of an upper surface of the source region is flat.
- 6. (Original) The semiconductor device according to Claim 2, wherein a part of an upper surface of the source region is flat.
- 7. (Original) The semiconductor device according to Claim 5, wherein a part of an upper surface of the drain region is flat.
- 8. (Original) The semiconductor device according to Claim 6, wherein a part of an upper surface of the drain region is flat.
  - 9 11. (Cancelled)
  - 12. (Currently Amended) A semiconductor device comprising:

# a support base;

an insulating layer formed on the support base;

a semiconductor layer formed on the insulating layer;

a source region formed in the semiconductor layer;

a drain region formed in the semiconductor layer;

a channel region formed between the source region and the drain region in the semiconductor layer;

a gate insulating layer formed above the channel region; and

a gate electrode formed above the gate insulating layer, the gate electrode having a major axis and a minor axis and first and second ends that are spaced apart along the major axis, overlap the semiconductor layer, and are in contact with the insulating layer;

wherein a boundary between the gate insulating layer and the channel region undulates and includes crests and troughs alternately spaced apart along the major axis of the gate electrode.

- 13. (Original) The semiconductor device according to Claim 12 wherein said boundary undulates in a sinusoidal pattern.
- 14. (Original) The semiconductor device according to Claim 12 wherein said boundary undulates in a curving pattern.